

**N -Channel Logic Level Enhancement Mode Power MOSFET**

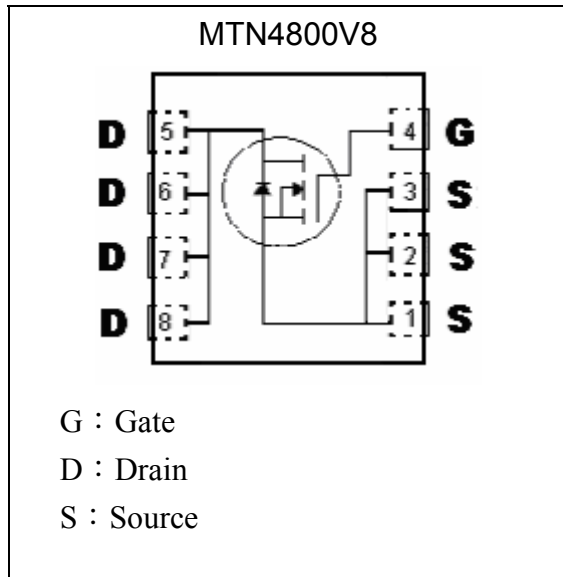
# MTN4800V8

BV <sub>DSS</sub>		30V
I <sub>D</sub>		18A
R <sub>DSON(TYP)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =10A	14mΩ
	V <sub>GS</sub> =4.5V, I <sub>D</sub> =8A	22mΩ

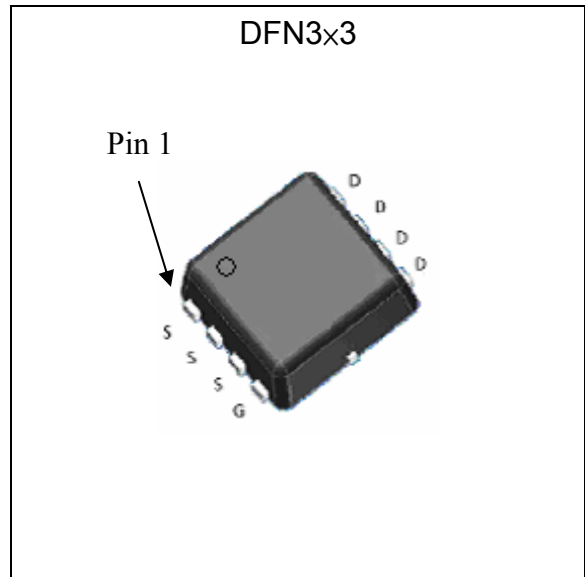
**Features**

- Low Gate Charge
- Simple Drive Requirement
- Pb-free lead plating package

**Equivalent Circuit**

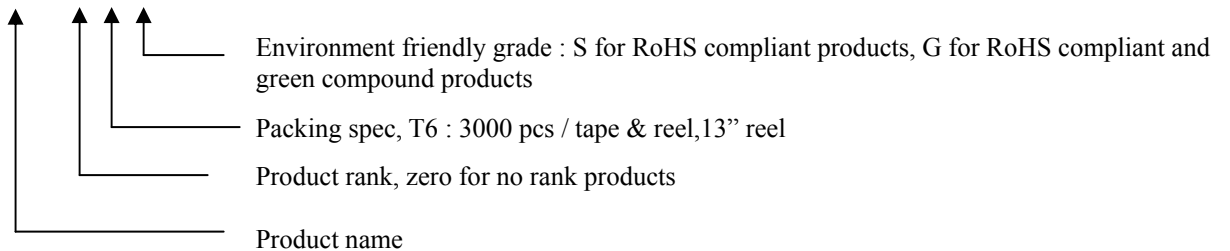


**Outline**



**Ordering Information**

Device	Package	Shipping
MTN4800V8-0-T6-G	DFN3x3 (Pb-free lead plating and halogen-free package)	3000 pcs / tape & reel





**Absolute Maximum Ratings** (T<sub>C</sub>=25°C, unless otherwise noted)

Parameter	Symbol	Limits	Unit
Drain-Source Voltage	V <sub>DS</sub>	30	V
Gate-Source Voltage	V <sub>GS</sub>	±20	
Continuous Drain Current @ T <sub>C</sub> =25°C	I <sub>D</sub>	18	A
Continuous Drain Current @ T <sub>C</sub> =100°C	I <sub>D</sub>	11.4	
Pulsed Drain Current *1	I <sub>DM</sub>	72	
Total Power Dissipation @T <sub>C</sub> =25°C	P <sub>D</sub>	8	W
Total Power Dissipation @T <sub>A</sub> =25°C		2.5	
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55~+150	°C

Note : \*1. Pulse width limited by maximum junction temperature  
 \*2. Duty cycle ≤ 1%

**Thermal Data**

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-case, max	R <sub>th,j-c</sub>	16	°C/W
Thermal Resistance, Junction-to-ambient, max	R <sub>th,j-a</sub>	50 *	°C/W

\* Surface mounted on a 1 in<sup>2</sup> pad of 2oz copper.

**Electrical Characteristics** (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Min.	Typ.	Max.	Unit	Test Conditions
<b>Static</b>					
BV <sub>DSS</sub>	30	-	-	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	-	0.02	-	V/°C	Reference to 25°C, I <sub>D</sub> =1mA
V <sub>GS(th)</sub>	1	1.7	2.5	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA
I <sub>GSS</sub>	-	-	±100	nA	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V
I <sub>DSS</sub>	-	-	1	μA	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C
	-	-	25	μA	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C
*R <sub>DS(ON)</sub>	-	14	20	mΩ	I <sub>D</sub> =10A, V <sub>GS</sub> =10V
	-	22	28		I <sub>D</sub> =8A, V <sub>GS</sub> =4.5V
*G <sub>FS</sub>	-	14	-	S	V <sub>DS</sub> =5V, I <sub>D</sub> =10A
<b>Dynamic</b>					
C <sub>iss</sub>	-	697	-	pF	V <sub>DS</sub> =25V, V <sub>GS</sub> =0, f=1MHz
C <sub>oss</sub>	-	61	-		
C <sub>rss</sub>	-	54	-		
t <sub>d(ON)</sub>	-	10	-	ns	V <sub>DS</sub> =15V, I <sub>D</sub> =1A, V <sub>GS</sub> =10V, R <sub>G</sub> =6Ω, R <sub>D</sub> =15Ω
t <sub>r</sub>	-	5	-	ns	
t <sub>d(OFF)</sub>	-	18	-	ns	
t <sub>f</sub>	-	14	-	ns	
Q <sub>g</sub>	-	9	-	nC	V <sub>DS</sub> =15V, I <sub>D</sub> =10A, V <sub>GS</sub> =10V,
Q <sub>gs</sub>	-	2.3	-	nC	
Q <sub>gd</sub>	-	3.4	-	nC	

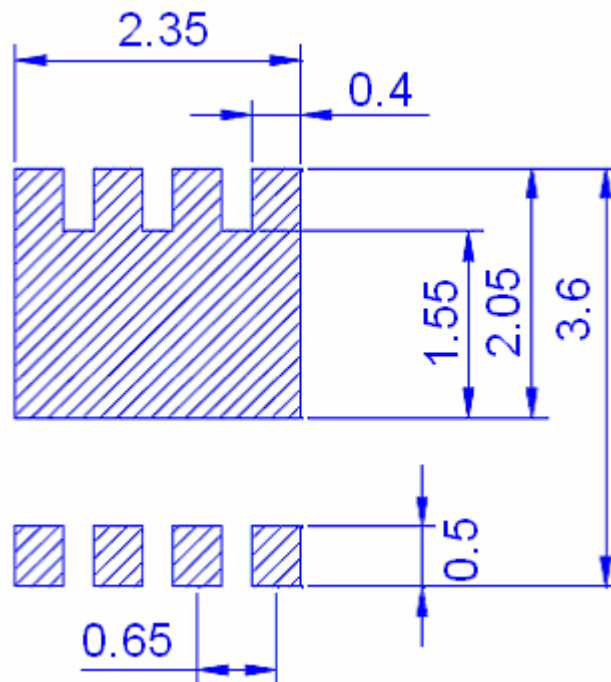
\*Pulse Test : Pulse Width ≤300μs, Duty Cycle ≤2%

**Source Drain Diode**

Symbol	Min.	Typ.	Max.	Unit	Test Conditions
*I <sub>S</sub>	-	-	4	A	
*I <sub>SM</sub>	-	-	16		
*V <sub>SD</sub>	-	0.8	1.3	V	I <sub>S</sub> =4A, V <sub>GS</sub> =0V
*T <sub>rr</sub>	-	9	-	ns	I <sub>S</sub> =4A, V <sub>GS</sub> =0V, dI/dt=100A/μs
Q <sub>rr</sub>	-	20	-	nC	

\*Pulse Test : Pulse Width ≤300μs, Duty Cycle≤2%

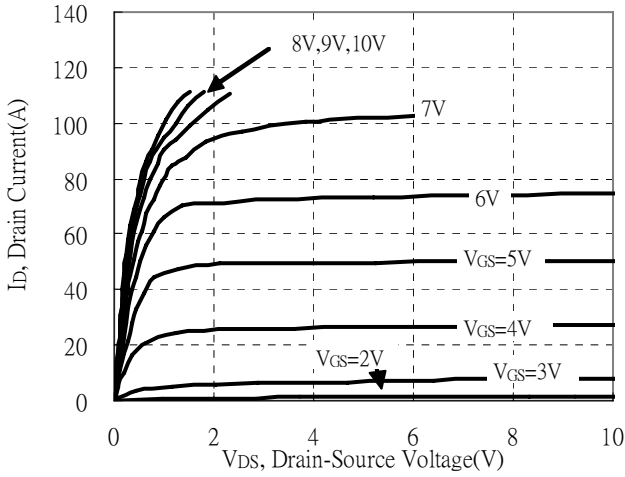
**Recommended Soldering Footprint**



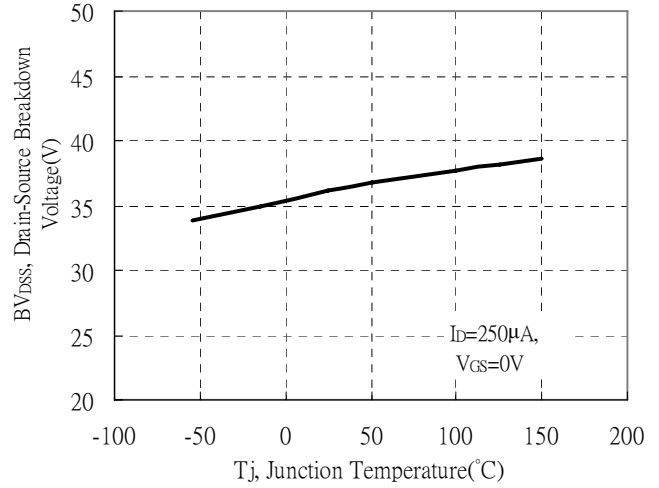
unit : mm

## Typical Characteristics

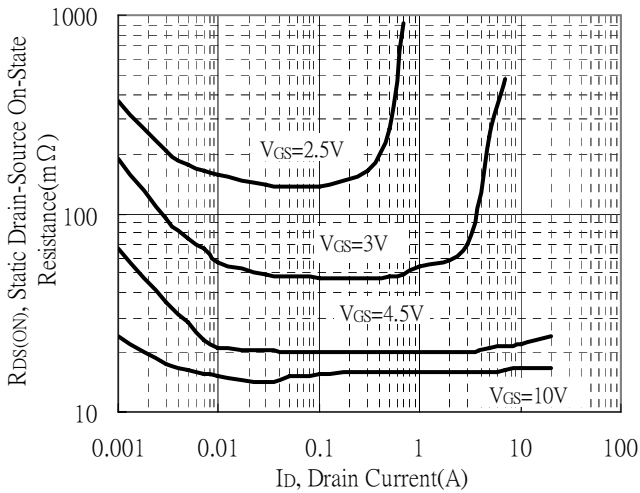
Typical Output Characteristics



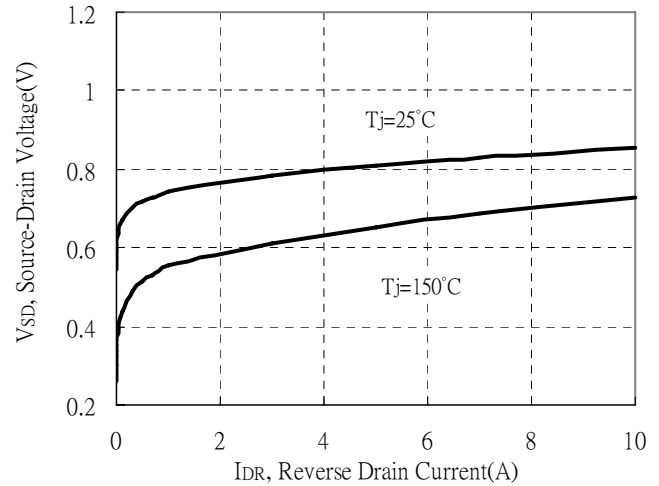
Brekdown Voltage vs Ambient Temperature



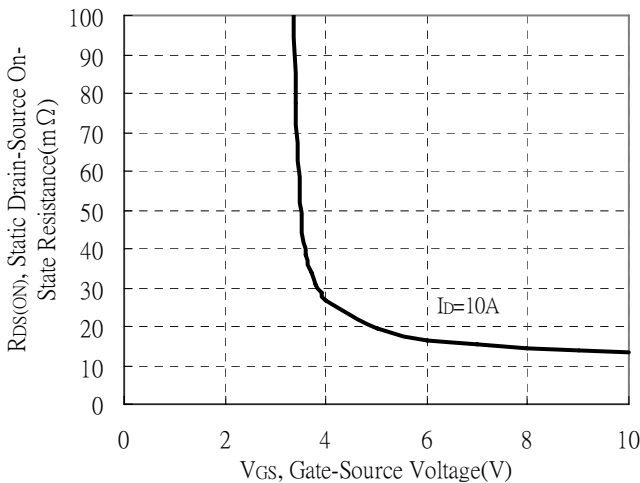
Static Drain-Source On-State resistance vs Drain Current



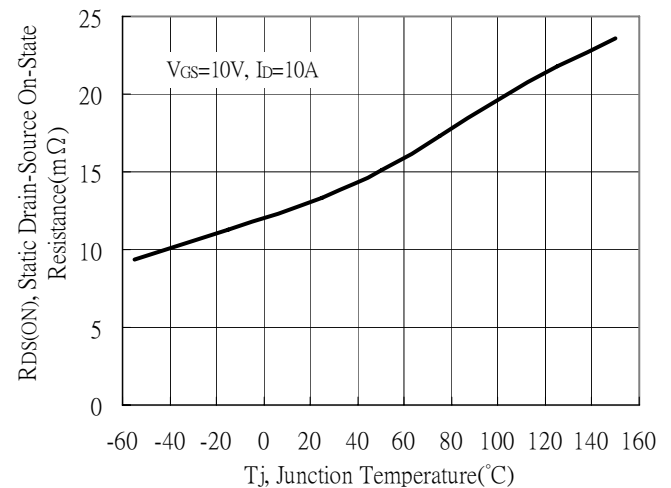
Reverse Drain Current vs Source-Drain Voltage



Static Drain-Source On-State Resistance vs Gate-Source Voltage

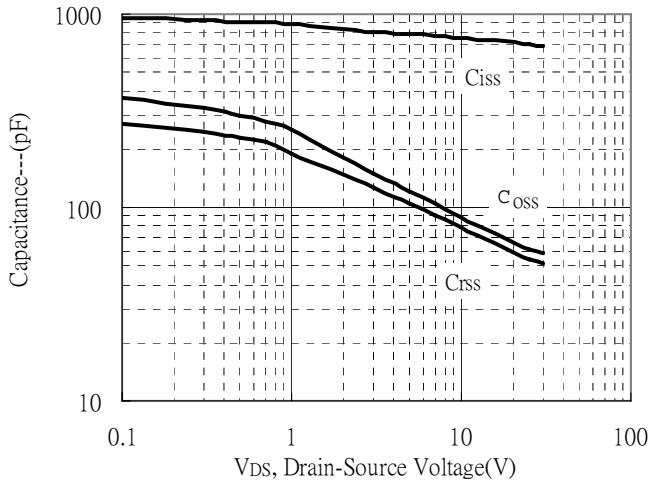


Drain-Source On-State Resistance vs Junction Temperature

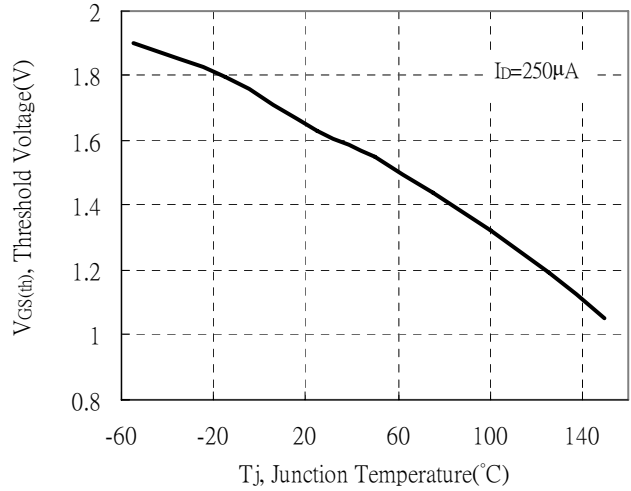


**Typical Characteristics(Cont.)**

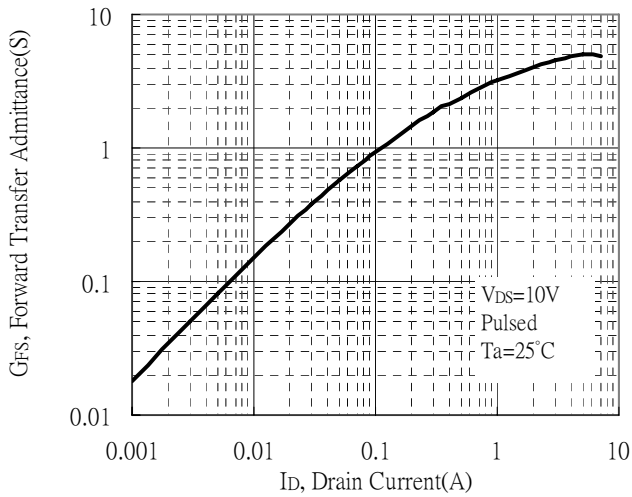
Capacitance vs Drain-to-Source Voltage



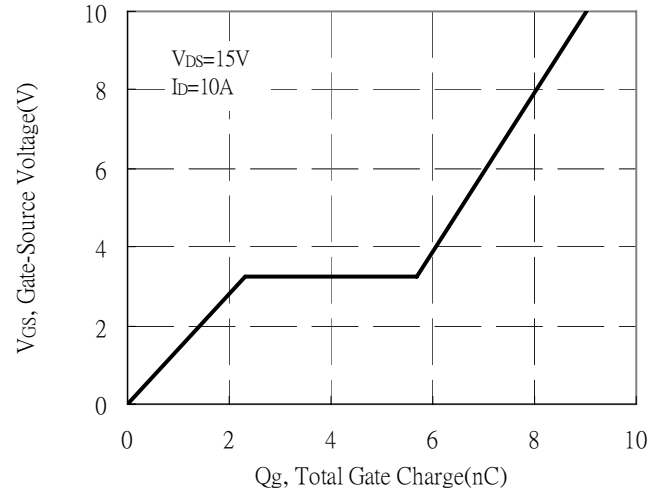
Threshold Voltage vs Junction Temperature



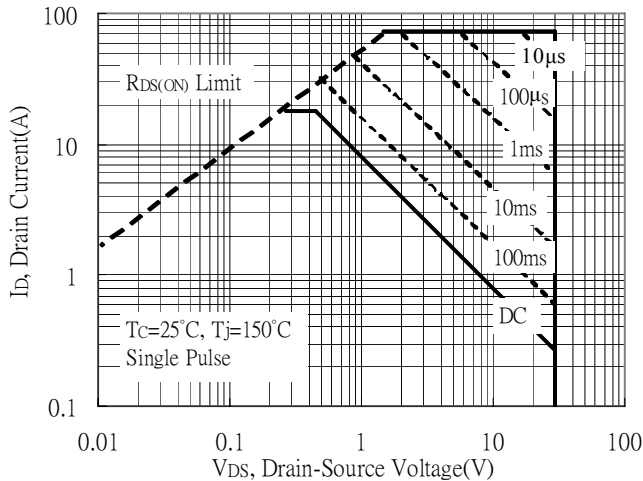
Forward Transfer Admittance vs Drain Current



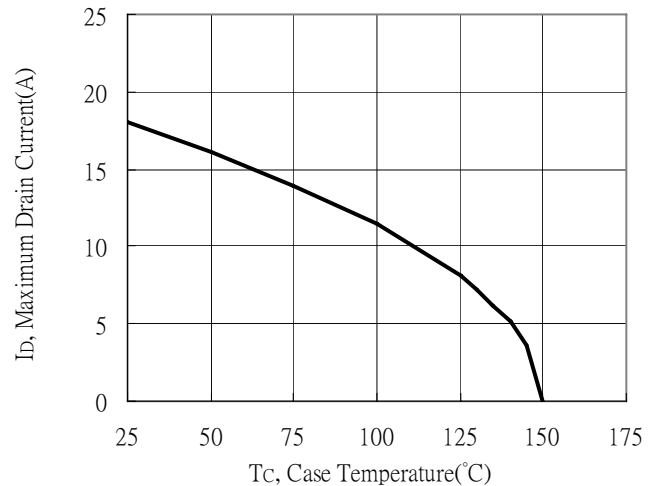
Gate Charge Characteristics



Maximum Safe Operating Area

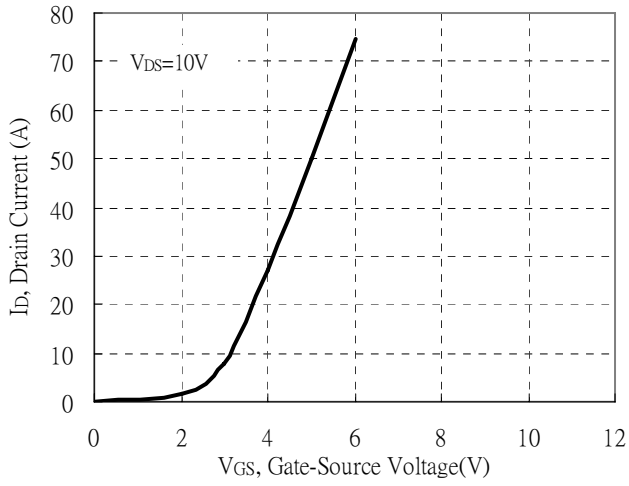


Maximum Drain Current vs Case Temperature

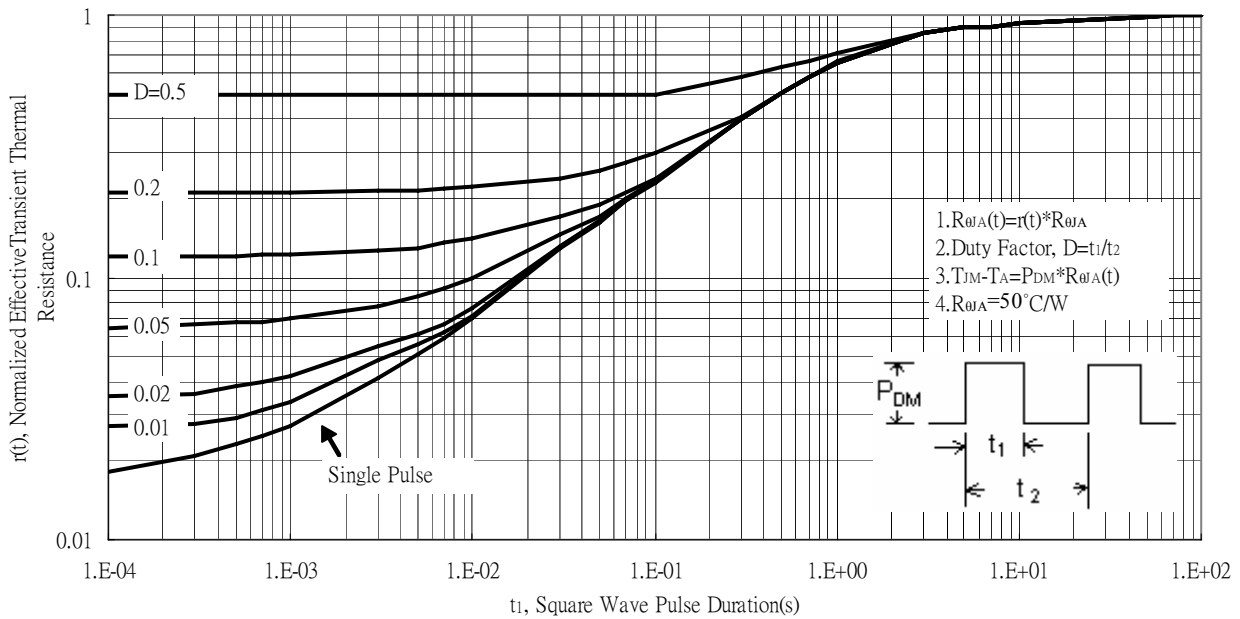


**Typical Characteristics(Cont.)**

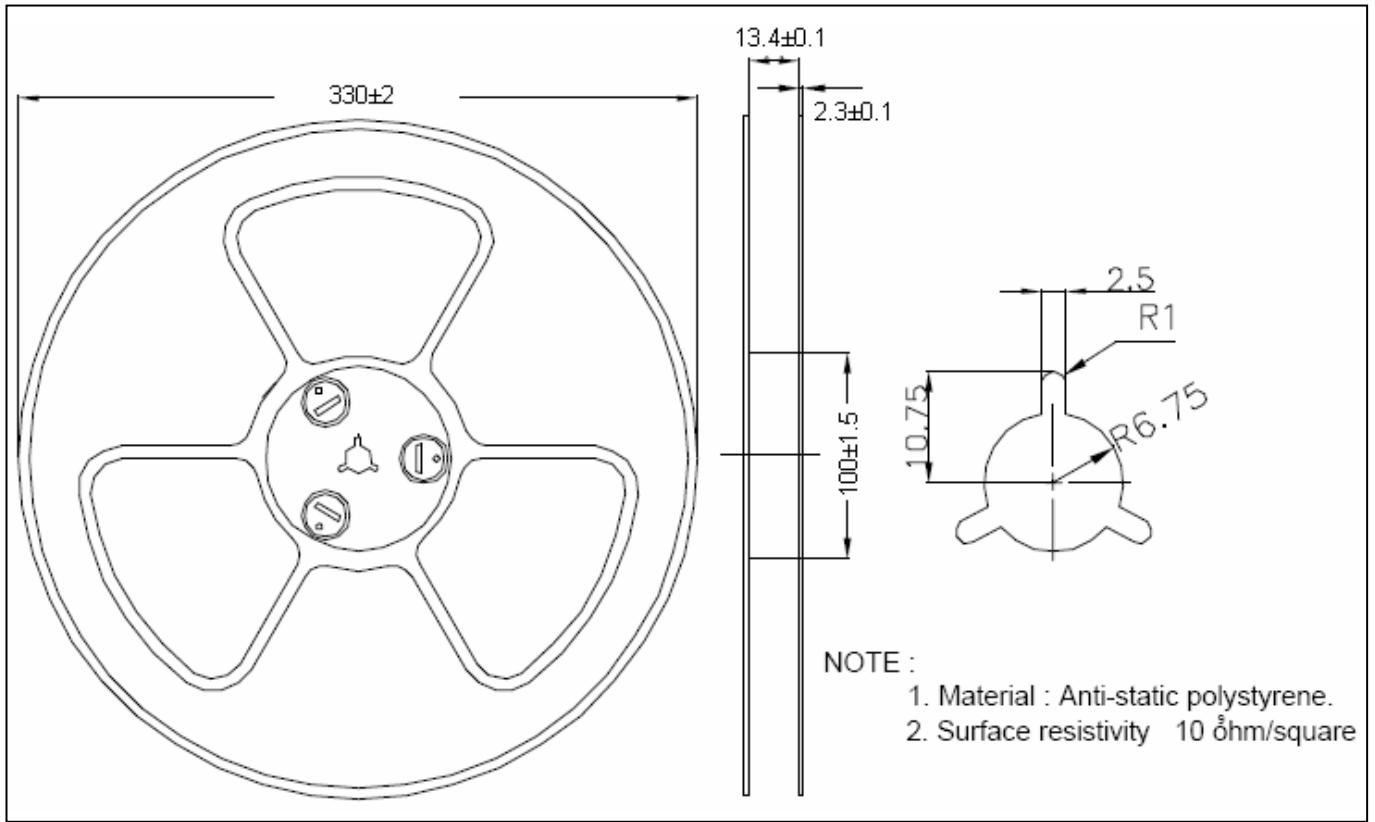
Typical Transfer Characteristics



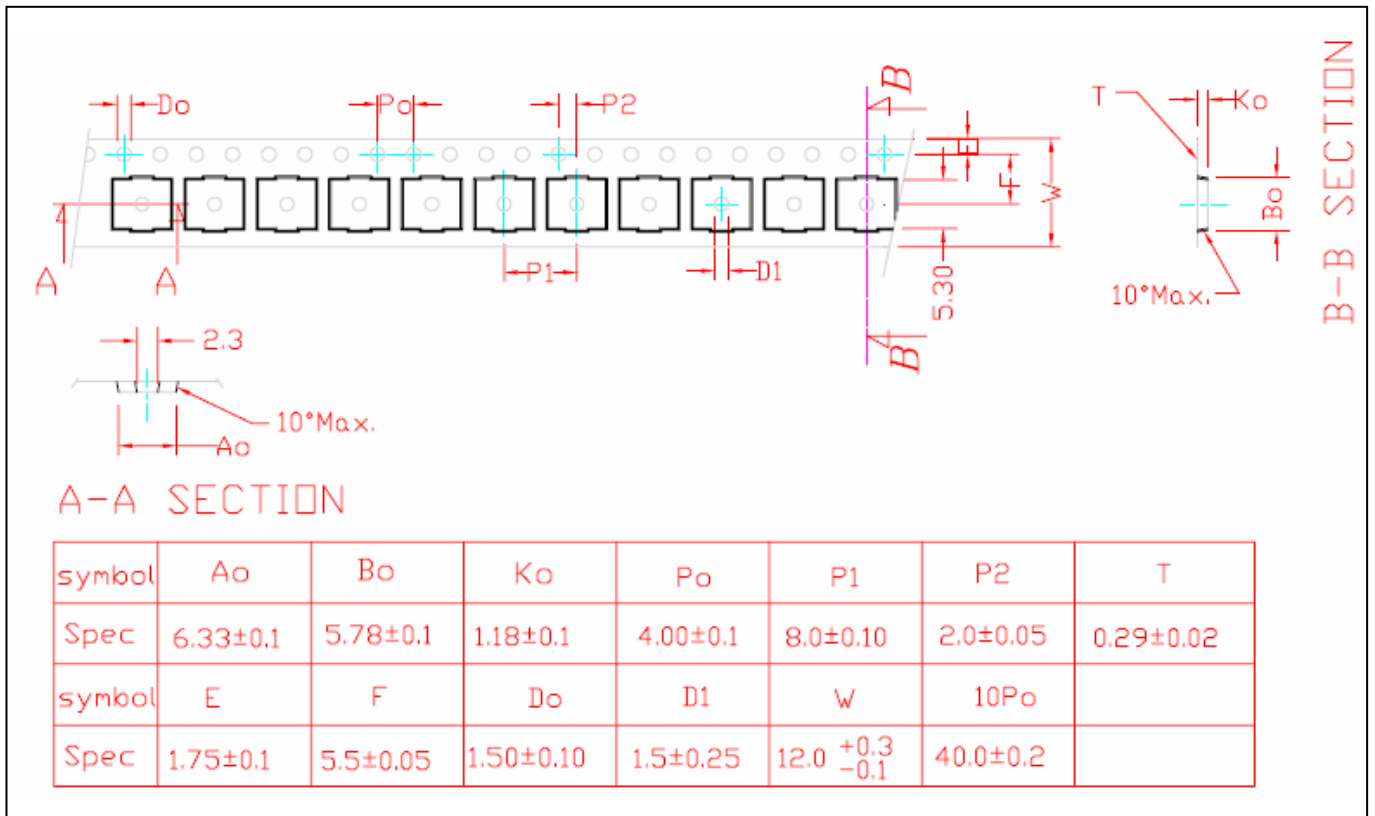
Transient Thermal Response Curves



**Reel Dimension**



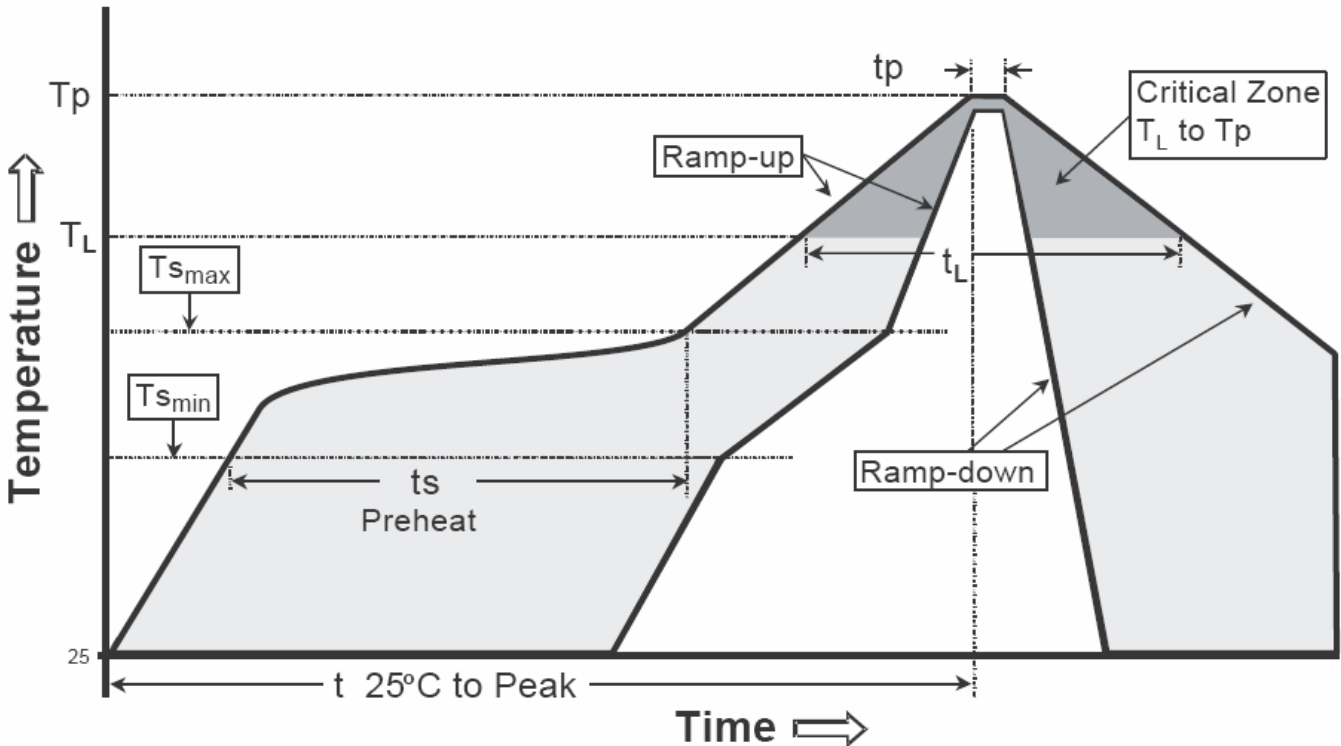
**Carrier Tape Dimension**



**Recommended wave soldering condition**

Product	Peak Temperature	Soldering Time
Pb-free devices	260 +0/-5 °C	5 +1/-1 seconds

**Recommended temperature profile for IR reflow**

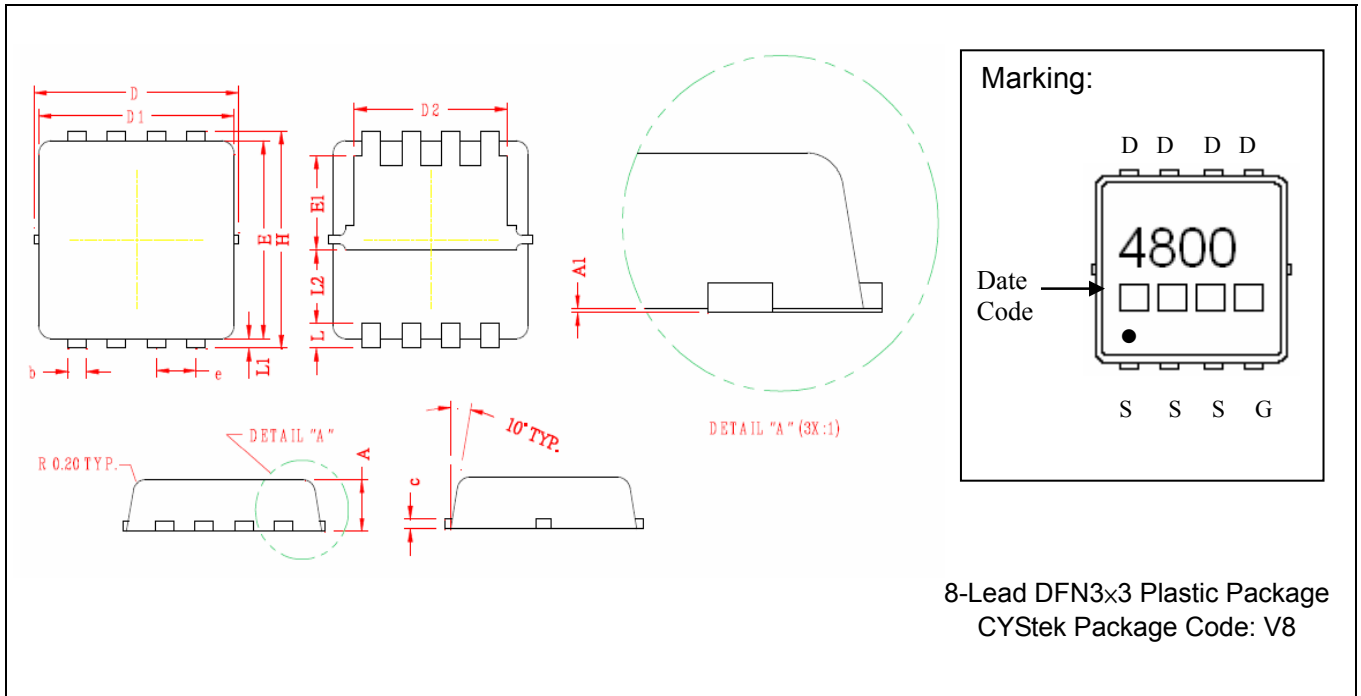


Profile feature	Sn-Pb eutectic Assembly	Pb-free Assembly
Average ramp-up rate (T <sub>smax</sub> to T <sub>p</sub> )	3°C/second max.	3°C/second max.
Preheat		
-Temperature Min(T <sub>s min</sub> )	100°C	150°C
-Temperature Max(T <sub>s max</sub> )	150°C	200°C
-Time(t <sub>s min</sub> to t <sub>s max</sub> )	60-120 seconds	60-180 seconds
Time maintained above:		
-Temperature (T <sub>L</sub> )	183°C	217°C
- Time (t <sub>L</sub> )	60-150 seconds	60-150 seconds
Peak Temperature(T <sub>P</sub> )	240 +0/-5 °C	260 +0/-5 °C
Time within 5°C of actual peak temperature(tp)	10-30 seconds	20-40 seconds
Ramp down rate	6°C/second max.	6°C/second max.
Time 25 °C to peak temperature	6 minutes max.	8 minutes max.

Note : All temperatures refer to topside of the package, measured on the package body surface.



**DFN3x3 Dimension**



\*: Typical

DIM	Inches		Millimeters		DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
A	0.0276	0.0354	0.70	0.90	E	0.1181	0.1260	3.00	3.20
A1	0.0000	0.0197	0.00	0.50	E1	0.0531	0.0610	1.35	1.55
b	0.0094	0.0138	0.24	0.35	e	0.0256	BSC	0.65	BSC
c	0.0039	0.0079	0.10	0.20	H	0.1260	0.1339	3.20	3.40
D	0.1280	0.1339	3.25	3.40	L	0.0118	0.0197	0.30	0.50
D1	0.1201	0.1280	3.05	3.25	L1	0.0039	0.0079	0.10	0.20
D2	0.0945	0.1024	2.40	2.60	L2	0.0445	REF	1.13	REF

**Notes:** 1.Controlling dimension: millimeters.  
 2.Maximum lead thickness includes lead finish thickness, and minimum lead thickness is the minimum thickness of base material.  
 3.If there is any question with packing specification or packing method, please contact your local CYStek sales office.

**Material:**

- Lead: pure tin plated.
- Mold Compound: Epoxy resin family, flammability solid burning class: UL94V-0.

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